

**Search Notes**

Application/Control No.

10/665,611

Examiner

Aung T. Win

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
370	332	5/10/2007	ATW
370	231-235	5/10/2007	ATW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
keyword searches	5/9/2007	ATW
searched by keywords in combination with listed subclasses	5/10/2007	ATW